

SiC UV avalanche photodiode

General Features:

- Broad band UVA+UVB+UVC avalanche photodiode
- Linear and Geiger mode operation
- Single photon counting capability
- Good visible blindness
- TO-46 metal housing



Model: SPAD-ABC-S

Applications: UV fluorescence detection, UV ladar and communication, remote flame sensing

Performance Specifications:

Parameter Description	Test Conditions	Specifications			l lmita		
		Min.	Тур.	Max.	Units		
Effective Optical Diameter			120		μm		
Linear Mode Parameters (Case temperature 300 K, all voltage and currents are reverse biased)							
Breakdown voltage, V _b	M>1		180		V		
Temperature coefficient of V _b	Between 300 K and 473 K, linear approximation		0.034		V/K		
Quantum Efficiency, QE	280 nm, M=1 (linear mode)		35		%		
Total Dark Current, I _d	M=10		10		рА		
Geiger Mode Parameters							
Dark Count Rate, DCR	Case temperature 300 K, 2 V overbias		10		kHz		
Photon Detection Efficiency, PDE	Case temperature 300 K, 280 nm, 2 V overbias		10		%		

Maximum Ratings:

Parameters	Conditions	Min.	Max.	Units
Forward Current	Continuous bias		1	mA
Forward Voltage	Continuous bias		5	V
Reverse Current	Continuous bias		0.1	mA
Reverse Voltage	Continuous bias		(V _b +5)	V
Reverse Voltage	Pulsed (gated operation)		(V _b +7)	V
Optical Power	Continuous wave (CW)		10	μW
Case Temperature		-20	100	°C

Note: maximum ratings indicate conditions that the device can be exposed for short periods of time without damage. Although there are reports that SiC APDs can operate at temperatures above 150 °C, these devices have not yet been tested to establish their reliability characteristics at very high temperature and under extreme conditions of thermal cycling.



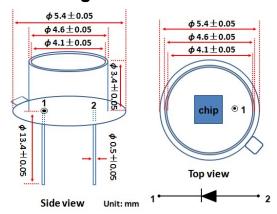
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Spectral response

0.12 10⁻¹ M=1 0.09 Responsivity (A/W) 10 0.06 10 0.03 0.00 10⁻⁶ 200 240 280 320 360 400 Wavelength (nm)

Package dimensions



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